



CRIS

APR
19
1993
Attorney Docket No.: 57017.P025

Patent

In re the Application of: MATTHEWS, J.

Serial No.: 07/863,791 (inventor(s))

Filed: APRIL 6, 1992

RECEIVED

For: METHOD FOR IMPROVED LITHOGRAPHIC PATTERNING IN A SEMICONDUCTOR

APR 22 1993

FABRICATION PROCESS

(title)

THE COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D.C. 20231

GROUP 150

SIR: Transmitted herewith is an Amendment for the above application.

Small entity status of this application under 37 C.F.R. §§ 1.9 and 1.27 has been established by a verified statement previously submitted.

A verified statement to establish small entity status under 37 C.F.R. §§ 1.9 and 1.27 is enclosed.

No additional fee is required.

The fee has been calculated as shown below:

	(Col. 1)	(Col. 2)	(Col. 3)	SMALL ENTITY	OTHER THAN A SMALL ENTITY
Total Claims	Claims Remaining After Amd.	Highest No. Previously Paid For	Present Extra	Rate x10 \$	Rate x20 \$
Indep. Claims	Minus	**		Rate x30 \$	Rate x60 \$
		***		Rate +100 \$	Rate +200 \$
	First Presentation of Multiple Dependent Claim(s)			Total Add. Fee \$	Total Add. Fee \$

* If the entry in Col. 1 is less than the entry in Col. 2, write "0" in Col. 3.

** If the "Highest No. Previously Paid For" IN THIS SPACE is less than 20, write "20" in this space.

*** If the "Highest No. Previously Paid For" IN THIS SPACE is less than 3, write "3" in this space. The "Highest No. Previously Paid For" (Total or Independent) is the highest number found from the equivalent box in Col. 1 of a prior amendment or the number of claims originally filed.

A check in the amount of \$ _____ is attached for presentation of additional claim(s).

Applicant(s) hereby Petition(s) for an Extension of Time of _____ month(s) pursuant to 37 C.F.R. § 1.136(a).

A check for \$ _____ is attached for processing fees under 37 C.F.R. § 1.17.

Please charge my Deposit Account No. 02-2666 the amount of \$ _____.

A duplicate copy of this sheet is enclosed.

The Commissioner is hereby authorized to charge payment of the following fees associated

with this communication or credit any overpayment to Deposit Account No. 02-2666
(a duplicate copy of this sheet is enclosed):

Any additional filing fees required under 37 C.F.R. § 1.16 for presentation of extra claims.

Any extension or petition fees under 37 C.F.R. § 1.17.

Date: 4/13/93

12400 Wilshire Boulevard
Seventh Floor
Los Angeles, California 90025
(408) 720-8598

BLAKELY SOKOLOFF TAYLOR & ZAFMAN

Bradley J. Bereznak

Reg. No. 33,474

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class mail with sufficient postage in an envelope addressed to the Commissioner of Patents and Trademarks, Washington, D.C. 20231

on April 13, 1993

Date of Deposit

Pearl E. Dworkin

Name of Person Mailing Correspondence

Signature

4/13/93

Date



EAR
05/1993
5/a

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of
MATTHEWS, J.
Serial No. 07/863,791
Filing Date: April 6, 1992
For: METHOD FOR IMPROVED
LITHOGRAPHIC PATTERNING IN A
SEMICONDUCTOR FABRICATION
PROCESS

)
)
)
)
)
)
)

Examiner: Dodson, S.
Art Unit: 1503

RECEIVED
APR 22 1993
GROUP 150

Amendment

Box Non-Fee Amendments (Pats)
Commissioner of Patents and Trademarks
Washington, D.C. 20231

Sir:

In response to the Office Action dated March 29, 1993, please enter the following amendment and consider the following remarks:

IN THE SPECIFICATION:

On page 4, line 9, change "rediation" to -- radiation --.

On page 7, line 32, delete ".".

IN THE CLAIMS:

Please cancel claim 13 without prejudice.

*Sub
D
A*

1. (Amended) A method of printing a two-dimensional feature on a substrate, said feature having first and second edges spaced in close proximity to one another, said method comprising the steps of:
 - (a) depositing a radiation-sensitive material on said substrate;
 - (b) providing a first mask image segment which corresponds to said first edge;
 - (c) exposing said first mask image segment with radiation using an imaging tool to produce a first pattern edge gradient, said first pattern edge gradient defining said first edge of said two-dimensional feature in said material;

X